



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Transcat–Montreal
9900 Côte-de-Liesse
Montréal, QC H8T 1A1 Canada

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 August 2027

Certificate Number: AC-2489.28



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Transcat–Montreal
9900 Côte-de-Liesse
Montréal, QC H8T 1A1 Canada
Nuccio Mercuri 888-886-9833

CALIBRATION

ISO/IEC 17025 Accreditation Granted: **22 August 2025**

Certificate Number: **AC-2489.28** Certificate Expiry Date: **22 August 2027**

Acoustics and Vibration

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Acceleration – Dynamic Amplitude Sensitivity: 10 mV/g	(0.1 to 10) g (5 to 9) Hz (10 to 99) Hz 100 Hz (101 to 920) Hz (921 to 5 000) Hz (5 001 to 9 999) Hz (10 to 15) kHz	2.2 % of reading 1.7 % of reading 1.3 % of reading 1.4 % of reading 1.7 % of reading 2.2 % of reading 3.7 % of reading	Comparison to Air Bearing Calibration Shaker

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	Up to 100 μ A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz 100 μ A to 1 mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz	0.46 % of reading + 35 nA 0.17 % of reading + 35 nA 0.072 % of reading + 35 nA 0.072 % of reading + 35 nA 0.46 % of reading + 0.23 μ A 0.17 % of reading + 0.23 μ A 0.071 % of reading + 0.23 μ A 0.038 % of reading + 0.23 μ A	Comparison to Agilent 3458A 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	(1 to 10) mA		Comparison to Agilent 3458A 8.5 Digit Multimeter
	(10 to 20) Hz	0.46 % of reading + 2.3 μ A	
	(20 to 45) Hz	0.17 % of reading + 2.3 μ A	
	(45 to 100) Hz	0.071 % of reading + 2.3 μ A	
	100 Hz to 5 kHz	0.038 % of reading + 2.3 μ A	
	(10 to 100) mA		
	(10 to 20) Hz	0.48 % of reading + 23 μ A	
	(20 to 45) Hz	0.17 % of reading + 23 μ A	
	(45 to 100) Hz	0.071 % of reading + 23 μ A	
	100 Hz to 5 kHz	0.037 % of reading + 23 μ A	
	100 mA to 1 A		
	(10 to 20) Hz	0.46 % of reading + 0.23 mA	
AC Current – Measure ¹	(20 to 45) Hz	0.19 % of reading + 0.23 mA	Comparison to Keysight 34465A 6.5 Digit Multimeter
	(45 to 100) Hz	0.097 % of reading + 0.23 mA	
	100 Hz to 5 kHz	0.12 % of reading + 0.23 mA	
	3 Hz to 5 kHz		
AC Current – Source ¹	(1 to 3) A	0.23% of reading + 1.2 mA	Comparison to Fluke 5720A Multiproduct Calibrator
	(3 to 5) A	0.15% of reading + 4 mA	
	(5 to 10) A	0.35% of reading + 4.1 mA	
	Up to 220 μ A		
	(10 to 20) Hz	0.03 % of reading + 16 nA	
	(20 to 40) Hz	0.019 % of reading + 10 nA	
	40 Hz to 1 kHz	0.015 % of reading + 8 nA	
	(1 to 5) kHz	0.03 % of reading + 12 nA	
	(5 to 10) kHz	0.11 % of reading + 65 nA	
	(0.22 to 2.2) mA		
	(10 to 20) Hz	0.03 % of reading + 40 nA	
	(20 to 40) Hz	0.018 % of reading + 35 nA	
	40 Hz to 1 kHz	0.013 % of reading + 35 nA	
	(1 to 5) kHz	0.021 % of reading + 0.11 μ A	
	(5 to 10) kHz	0.11 % of reading + 0.65 μ A	
	(2.2 to 22) mA		
	(10 to 20) Hz	0.039 % of reading + 0.4 μ A	
	(20 to 40) Hz	0.018 % of reading + 0.35 μ A	
	40 Hz to 1 kHz	0.014 % of reading + 0.35 μ A	
	(1 to 5) kHz	0.021 % of reading + 0.55 μ A	
	(5 to 10) kHz	0.11 % of reading + 5 μ A	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	(22 to 220) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (0.22 to 2.2) A 20 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.033 % of reading + 4 μ A 0.018 % of reading + 3.5 μ A 0.014 % of reading + 2.5 μ A 0.021 % of reading + 3.5 μ A 0.11 % of reading + 10 μ A 0.027 % of reading + 35 μ A 0.046 % of reading + 80 μ A 0.7 % of reading + 0.16 mA	Comparison to Fluke 5720A Multiproduct Calibrator
AC Current – Source ¹	(2.2 to 11) A 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.048 % of reading + 0.17 mA 0.096 % of reading + 0.38 mA 0.36 % of reading + 0.75 mA	Comparison to Fluke 5720A Multiproduct Calibrator, Fluke 5725A Amplifier
AC Current – Source ¹	(11 to 20.5) A (45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz	0.095 % of reading + 3.9 mA 0.12 % of reading + 3.9 mA 2.3 % of reading + 3.9 mA	Comparison to Fluke 5522A Multiproduct Calibrator
AC Clamp-on Ammeters (Toroidal Type) Transformer Type Sensor ¹	(20 to 150) A (45 to 65) Hz (65 to 440) Hz (150 to 1 000) A (45 to 65) Hz (65 to 440) Hz	0.3 % of reading + 26 mA 0.83 % of reading + 47 mA 0.35 % of reading + 0.12 A 1.1 % of reading + 0.22 A	Comparison to Fluke 5522A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
AC Clamp-on Ammeters (Non-Toroidal Type) Hall Effect Sensor ¹	(20 to 150) A (45 to 65) Hz (65 to 440) Hz (150 to 1 000) A (45 to 65) Hz (65 to 440) Hz	0.57 % of reading + 0.25 A 1 % of reading + 0.25 A 0.6 % of reading + 0.9 A 1.3 % of reading + 0.92 A	Comparison to Fluke 5522A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
DC Clamp-on Ammeters (Non-Toroidal Type) Transformer Type Sensor ¹	(20 to 150) A (150 to 1 000) A	0.51 % of reading + 0.14 A 0.51 % of reading + 0.5 A	Comparison to Fluke 5522A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	Up to 10 mV		Comparison to Agilent 3458A 8.5 Digit Multimeter
	(1 to 40) Hz	0.04 % of reading + 3.5 μ V	
	40 Hz to 1 kHz	0.03 % of reading + 1.2 μ V	
	(1 to 20) kHz	0.04 % of reading + 1.2 μ V	
	(20 to 50) kHz	0.15 % of reading + 1.2 μ V	
	(50 to 100) kHz	0.59 % of reading + 1.2 μ V	
	(100 to 300) kHz	4.6 % of reading + 2.3 μ V	
	300 kHz to 1 MHz	1.5 % of reading + 5.8 μ V	
	(1 to 4) MHz	8.1 % of reading + 8.1 μ V	
	(10 to 100) mV		
	(1 to 40) Hz	0.013 % of reading + 4.8 μ V	
	40 Hz to 1 kHz	0.009 7 % of reading + 2.3 μ V	
	(1 to 20) kHz	0.017 % of reading + 2.3 μ V	
	(20 to 50) kHz	0.038 % of reading + 2.3 μ V	
	(50 to 100) kHz	0.093 % of reading + 2.3 μ V	
	(100 to 300) kHz	0.36 % of reading + 12 μ V	
	300 kHz to 1 MHz	1.2 % of reading + 12 μ V	
	(1 to 2) MHz	1.8 % of reading + 12 μ V	
	(2 to 4) MHz	4.7 % of reading + 81 μ V	
	(4 to 8) MHz	4.7 % of reading + 92 μ V	
	(8 to 10) MHz	17 % of reading + 0.12 mV	
	(0.1 to 1) V		
	(1 to 40) Hz	0.008 8 % of reading + 46 μ V	
	40 Hz to 1 kHz	0.008 3 % of reading + 23 μ V	
	(1 to 20) kHz	0.017 % of reading + 23 μ V	
	(20 to 50) kHz	0.036 % of reading + 23 μ V	
	(50 to 100) kHz	0.093 % of reading + 23 μ V	
	(100 to 300) kHz	0.36 % of reading + 0.12 mV	
	300 kHz to 1 MHz	1.2 % of reading + 0.12 mV	
	(1 to 2) MHz	1.8 % of reading + 0.12 mV	
	(2 to 4) MHz	4.6 % of reading + 0.81 mV	
	(4 to 8) MHz	4.6 % of reading + 0.92 mV	
	(8 to 10) MHz	17 % of reading + 1.2 mV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(1 to 10) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 2) MHz (2 to 4) MHz (4 to 8) MHz (8 to 10) MHz (10 to 100) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (100 to 700) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.009 5 % of reading + 0.46 mV 0.002 3 % of reading + 0.23 mV 0.017 % of reading + 0.23 mV 0.036 % of reading + 0.23 mV 0.093 % of reading + 0.23 mV 0.36 % of reading + 1.2 mV 1.2 % of reading + 1.2 mV 1.8 % of reading + 2 mV 4.6 % of reading + 8.1 mV 4.6 % of reading + 9.2 mV 17 % of reading + 12 mV 0.024 % of reading + 4.6 mV 0.024 % of reading + 2.3 mV 0.024 % of reading + 2.3 mV 0.041 % of reading + 2.3 mV 0.14 % of reading + 2.3 mV 0.46 % of reading + 12 mV 1.7 % of reading + 12 mV 0.048 % of reading + 46 mV 0.048 % of reading + 23 mV 0.071 % of reading + 23 mV 0.19 % of reading + 23 mV 0.35 % of reading + 23 mV	Comparison to Agilent 3458A 8.5 Digit Multimeter
	(1 to 10) kV (10 to 200) Hz (200 to 450) Hz (450 to 600) Hz (10 to 35) kV (30 to 200) Hz (200 to 450) Hz (450 to 600) Hz (35 to 70) kV (30 to 100) Hz (100 to 450) Hz (450 to 600) Hz	0.14 % of reading + 0.17 V 0.46 % of reading + 0.17 V 0.86 % of reading + 0.17 V 0.11 % of reading + 0.81 V 0.7 % of reading + 0.81 V 1.5 % of reading + 0.81 V 0.14 % of reading + 1 V 0.7 % of reading + 1 V 3 % of reading + 1 V	
AC High Voltage – Measure ¹			Comparison to Vitretek 4700 High Voltage Meter with Associated Probes

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC High Voltage – Measure ¹	(70 to 100) kV (30 to 100) Hz (100 to 450) Hz (450 to 600) Hz	0.2 % of reading + 1.3 V 1.2 % of reading + 1.3 V 17 % of reading + 1.3V	Comparison to Vitrek 4700 High Voltage Meter with Associated Probes
AC Voltage – Source ¹	Up to 2.2 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 o 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz (2.2 to 22) mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 o 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz (22 to 220) mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 o 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz (0.22 to 2.2) V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 o 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz	0.16 % of reading + 4 μV 0.1 % of reading + 4 μV 0.078 % of reading + 4 μV 0.13 % of reading + 4 μV 0.17 % of reading + 5 μV 0.33 % of reading + 10 μV 0.47 % of reading + 20 μV 0.58 % of reading + 20 μV 0.042 % of reading + 4 μV 0.03 % of reading + 4 μV 0.014 % of reading + 4 μV 0.03 % of reading + 4 μV 0.058 % of reading + 5 μV 0.12 % of reading + 10 μV 0.16 % of reading + 20 μV 0.27 % of reading + 20 μV 0.028 % of reading + 12 μV 0.011 % of reading + 7 μV 0.008 5 % of reading + 7 μV 0.021 % of reading + 7 μV 0.047 % of reading + 17 μV 0.091 % of reading + 20 μV 0.14 % of reading + 25 μV 0.28 % of reading + 45 μV 0.027 % of reading + 40 μV 0.01 % of reading + 15 μV 0.004 8 % of reading + 8 μV 0.008 % of reading + 10 μV 0.012 % of reading + 30 μV 0.043 % of reading + 80 μV 0.1 % of reading + 0.2 mV 0.18 % of reading + 0.3 mV	Comparison to Fluke 5720A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	(2.2 to 22) V		Comparison to Fluke 5720A Multiproduct Calibrator
	(10 to 20) Hz	0.028 % of reading + 0.4 mV	
	(20 to 40) Hz	0.01 % of reading + 0.15 mV	
	40 Hz to 20 kHz	0.004 9 % of reading + 50 μ V	
	(20 to 50) kHz	0.008 3 % of reading + 0.1 mV	
	(50 to 100) kHz	0.011 % of reading + 0.2 mV	
	(100 to 300) kHz	0.03 % of reading + 0.6 mV	
	(300 to 500) kHz	0.1 % of reading + 2 mV	
	500 kHz to 1 MHz	0.17 % of reading + 3.2 mV	
	(22 to 220) V		
	(10 to 20) Hz	0.028 % of reading + 4 mV	
	(20 to 40) Hz	0.01 % of reading + 1.5 mV	
	40 Hz to 20 kHz	0.005 6 % of reading + 0.6 mV	
	(20 to 50) kHz	0.009 3 % of reading + 1 mV	
	(50 to 100) kHz	0.016 % of reading + 2.5 mV	
AC Voltage – Source ¹	(100 to 300) kHz	0.09 % of reading + 16 mV	
	(300 to 500) kHz	0.44 % of reading + 40 mV	
	500 kHz to 1 MHz	0.8 % of reading + 80 mV	
	(220 to 1 100) V		
	40 Hz to 1 kHz	0.011 % of reading + 4 mV	
AC Voltage – Source ¹	(1 to 20) kHz	0.017 % of reading + 6 mV	
	(20 to 30) kHz	0.061 % of reading + 11 mV	
AC Voltage – Source ¹	(220 to 750) V		Comparison to Fluke 5720A Multiproduct Calibrator, Fluke 5725A Amplifier
	(30 to 50) kHz	0.061 % of reading + 11 mV	
	(50 to 100) kHz	0.23 % of reading + 45 mV	
DC Current – Measure ¹	(0 to 100) μ A	33 μ A/A + 0.92 nA	Comparison to Agilent 3458A 8.5 Digit Multimeter
	100 μ A to 1 mA	29 μ A/A + 5.8 nA	
	(1 to 10) mA	29 μ A/A + 58 nA	
	(10 to 100) mA	46 μ A/A + 580 nA	
	100 mA to 1 A	0.013 % of reading + 12 μ A	
DC Current – Measure ¹	(1 to 3) A	0.2 % of reading + 0.6 mA	Comparison to Keysight 34465A 6.5 Digit Multimeter
	(3 to 5) A	0.12 % of reading + 1 mA	
	(5 to 10) A	0.32 % of reading + 1.1 mA	
DC Current – Source ¹	(0.22 to 220) μ A	41 μ A/A + 6 nA	Comparison to Fluke 5720A Multiproduct Calibrator
	(0.22 to 2.2) mA	36 μ A/A + 7 nA	
	(2.2 to 22) mA	36 μ A/A + 40 nA	
	(22 to 220) mA	48 μ A/A + 0.7 μ A	
	(0.22 to 2.2) A	57 μ A/A + 12 μ A	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Source ¹	(2.2 to 11) A	0.4 mA/A + 0.48 mA	Comparison to Fluke 5720A Multiproduct Calibrator, Fluke 5725A Amplifier
DC Current – Source ¹	(11 to 20) A	0.93 mA/A + 0.58 mA	Comparison to Fluke 5522A Multiproduct Calibrator
DC Voltage – Measure ¹	(0 to 100) mV (0.1 to 1) V (1 to 10) V (10 to 100) V (100 to 500) V (500 to 800) V (800 to 1 000) V	8.3 μ V/V + 0.58 μ V 5.3 μ V/V + 0.58 μ V 5.3 μ V/V + 0.58 μ V 7.7 μ V/V + 35 μ V 15 μ V/V + 0.12 mV 18 μ V/V + 0.12 mV 21 μ V/V + 0.12 mV	Comparison to Agilent 3458A Opt. 002 8.5 Digit Multimeter
DC High Voltage – Measure ¹	(1 to 10) kV (10 to 45) kV (35 to 70) kV (70 to 100) kV	0.04 % of reading + 40 mV 0.064 % of reading + 66 mV 0.09 % of reading + 80 mV 0.17 % of reading + 0.92 V	Comparison to Vitretek 4700 High Voltage Meter with Associated Probes
DC Voltage – Source ¹	(0 to 220) mV (0.22 to 2.2) V (2.2 to 11) V (11 to 22) V (22 to 220) V (220 to 1 100) V	8.5 μ V/V + 0.4 μ V 5.1 μ V/V + 0.7 μ V 4 μ V/V + 2.5 μ V 3.9 μ V/V + 4 μ V 6.2 μ V/V + 40 μ V 7.6 μ V/V + 0.4 mV	Comparison to Fluke 5720A Multiproduct Calibrator
DC Resistance – Measure ¹	(0 to 10) Ω (10 to 100) Ω 100 Ω to 1 k Ω (1 to 10) k Ω (10 to 100) k Ω 100 k Ω to 1 M Ω (1 to 10) M Ω (10 to 100) M Ω 100 M Ω to 1 G Ω	18 $\mu\Omega/\Omega$ + 58 $\mu\Omega$ 15 $\mu\Omega/\Omega$ + 0.58 m Ω 13 $\mu\Omega/\Omega$ + 0.58 m Ω 21 $\mu\Omega/\Omega$ + 5.8 m Ω 13 $\mu\Omega/\Omega$ + 58 m Ω 21 $\mu\Omega/\Omega$ + 2.3 Ω 62 $\mu\Omega/\Omega$ + 120 Ω 0.059 % of reading + 1.2 k Ω 0.82 % of reading + 12 k Ω	Comparison to Agilent 3458A 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Resistance – Source ¹ (Fixed Artifacts)	0 Ω	40 $\mu\Omega/\Omega$	Comparison to Fluke 5720A Multiproduct Calibrator
	1 Ω	98 $\mu\Omega/\Omega$	
	1.9 Ω	96 $\mu\Omega/\Omega$	
	10 Ω	24 $\mu\Omega/\Omega$	
	19 Ω	25 $\mu\Omega/\Omega$	
	100 Ω	11 $\mu\Omega/\Omega$	
	190 Ω	11 $\mu\Omega/\Omega$	
	1 k Ω	9.4 $\mu\Omega/\Omega$	
	1.9 k Ω	9.4 $\mu\Omega/\Omega$	
	10 k Ω	9.4 $\mu\Omega/\Omega$	
	19 k Ω	9.4 $\mu\Omega/\Omega$	
	100 k Ω	12 $\mu\Omega/\Omega$	
	190 k Ω	12 $\mu\Omega/\Omega$	
	1 M Ω	22 $\mu\Omega/\Omega$	
	1.9 M Ω	23 $\mu\Omega/\Omega$	
	10 M Ω	42 $\mu\Omega/\Omega$	
	19 M Ω	49 $\mu\Omega/\Omega$	
	100 M Ω	0.11 m Ω/Ω	
DC Resistance – Source ¹ (Simulation)	Up to 11 Ω	32 $\mu\Omega/\Omega + 0.78$ m Ω	Comparison to Fluke 5522A Multiproduct Calibrator
	(11 to 33) Ω	24 $\mu\Omega/\Omega + 1.2$ m Ω	
	(33 to 111) Ω	22 $\mu\Omega/\Omega + 1.1$ m Ω	
	(110 to 330) Ω	22 $\mu\Omega/\Omega + 1.6$ m Ω	
	330 Ω to 1.1 k Ω	22 $\mu\Omega/\Omega + 1.6$ m Ω	
	(1.1 to 3.3) k Ω	22 $\mu\Omega/\Omega + 16$ m Ω	
	(3.3 to 11) k Ω	22 $\mu\Omega/\Omega + 16$ m Ω	
	(11 to 33) k Ω	22 $\mu\Omega/\Omega + 0.16$ Ω	
	(33 to 110) k Ω	22 $\mu\Omega/\Omega + 0.16$ Ω	
	(110 to 330) k Ω	27 $\mu\Omega/\Omega + 1.6$ Ω	
	330 k Ω to 1.19 M Ω	26 $\mu\Omega/\Omega + 1.6$ Ω	
	(1.1 to 3.3) M Ω	66 $\mu\Omega/\Omega + 23$ Ω	
	(3.3 to 11) M Ω	0.1 m $\Omega/\Omega + 39$ Ω	
	(11 to 33) M Ω	0.19 m $\Omega/\Omega + 1.9$ k Ω	
	(33 to 110) M Ω	0.41 m $\Omega/\Omega + 2.3$ k Ω	
	(110 to 330) M Ω	0.23 % of reading + 78 k Ω	
	330 M Ω to 1.1 G Ω	12 % of reading + 0.39 M Ω	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Resistance – Source ¹ Up to 5 kV Voltage (Variable Artifact)	1 kΩ	0.12 Ω/kΩ	Comparison to IET Labs VRS-100-10-1k-BP High Resistance Decade Box
	10 kΩ	0.12 Ω/kΩ	
	100 kΩ	0.12 Ω/kΩ	
	1 MΩ	0.12 kΩ + 1.2 Ω/MΩ/V	
	10 MΩ	1.4 kΩ + 1.2 Ω/MΩ/V	
	100 MΩ	21 kΩ + 1.2 Ω/MΩ/V	
	1 GΩ	5.8 MΩ + 1.2 kΩ/GΩ/V	
	10 GΩ	62 MΩ + 2.3 kΩ/GΩ/V	
	100 GΩ	1.2 GΩ + 5.8 kΩ/GΩ/V	
	1 TΩ	23 GΩ + 12 MΩ/TΩ/V	
Electrical Simulation of RTD Indicating Devices – Source ¹	Pt 385, 100 Ω		Comparison to Fluke 5522A Multiproduct Calibrator
	(-200 to -80) °C	0.039 °C	
	(-80 to 0) °C	0.039 °C	
	(0 to 100) °C	0.054 °C	
	(100 to 300) °C	0.07 °C	
	(300 to 400) °C	0.078 °C	
	(400 to 630) °C	0.093 °C	
	(630 to 800) °C	0.18 °C	
	Pt 385, 200 Ω		
	-200 to -80) °C	0.031 °C	
	(-80 to 0) °C	0.031 °C	
	(0 to 100) °C	0.031 °C	
	(100 to 260) °C	0.039 °C	
	(260 to 300) °C	0.093 °C	
	(300 to 400) °C	0.1 °C	
	(400 to 600) °C	0.11 °C	
	(600 to 630) °C	0.12 °C	
	Pt 385, 500 Ω		
	(-200 to -80) °C	0.031 °C	
	(-80 to 0) °C	0.039 °C	
	(0 to 100) °C	0.039 °C	
	(100 to 260) °C	0.047 °C	
	(260 to 300) °C	0.062 °C	
	(300 to 400) °C	0.062 °C	
	(400 to 600) °C	0.07 °C	
	(600 to 630) °C	0.085 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicating Devices – Source ¹	Pt 385, 1 000 Ω		Comparison to Fluke 5522A Multiproduct Calibrator
	(-200 to -80) °C	0.023 °C	
	(-80 to 0) °C	0.023 °C	
	(0 to 100) °C	0.031 °C	
	(100 to 260) °C	0.039 °C	
	(260 to 300) °C	0.047 °C	
	(300 to 400) °C	0.054 °C	
	(400 to 600) °C	0.054 °C	
	(600 to 630) °C	0.18 °C	
	Pt 3916, 100 Ω		
	(-200 to -190) °C	0.19 °C	
	(-190 to -80) °C	0.031 °C	
	(-80 to 0) °C	0.039 °C	
	(0 to 100) °C	0.047 °C	
	(100 to 260) °C	0.054 °C	
	(260 to 300) °C	0.062 °C	
	(300 to 400) °C	0.07 °C	
	(400 to 600) °C	0.078 °C	
	(600 to 630) °C	0.018 °C	
	Pt 3926, 100 Ω		
	(-200 to -80) °C	0.039 °C	
	(-80 to 0) °C	0.039 °C	
	(0 to 100) °C	0.054 °C	
	(100 to 300) °C	0.07 °C	
	(300 to 400) °C	0.078 °C	
	(400 to 630) °C	0.093 °C	
	PtNi 385, 120 Ω		
	(-80 to 0) °C	0.062 °C	
	(0 to 100) °C	0.062 °C	
	(100 to 260) °C	0.1 °C	
	Cu 427, 10 Ω		
	(-100 to 260) °C	0.23 °C	
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type B		Comparison to Fluke 5522A Multiproduct Calibrator
	(600 to 800) °C	0.35 °C	
	(800 to 1 000) °C	0.28 °C	
	(1 000 to 1 550) °C	0.24 °C	
	(1 550 to 1 820) °C	0.26 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type C		Comparison to Fluke 5522A Multiproduct Calibrator
	(0 to 150) °C	0.24 °C	
	(150 to 650) °C	0.21 °C	
	(650 to 1 000) °C	0.24 °C	
	(1 000 to 1 800) °C	0.39 °C	
	(1 800 to 2 316) °C	0.65 °C	
	Type E		
	(-250 to -100) °C	0.39 °C	
	(-100 to -25) °C	0.13 °C	
	(-25 to 350) °C	0.12 °C	
	(350 to 650) °C	0.13 °C	
	(650 to 1 000) °C	0.17 °C	
	Type J		
	(-210 to -100) °C	0.21 °C	
	(-100 to -30) °C	0.13 °C	
	(-30 to 150) °C	0.12 °C	
	(150 to 760) °C	0.14 °C	
	(760 to 1 200) °C	0.18 °C	
	Type K		
	(-200 to -100) °C	0.26 °C	
	(-100 to -25) °C	0.15 °C	
	(-25 to 120) °C	0.13 °C	
	(120 to 1 000) °C	0.21 °C	
	(1 000 to 1 372) °C	0.31 °C	
	Type L		
	(-200 to -100) °C	0.29 °C	
	(-100 to 800) °C	0.21 °C	
	(800 to 900) °C	0.14 °C	
	Type N		
	(-200 to -100) °C	0.31 °C	
	(-100 to -25) °C	0.18 °C	
	(-25 to 120) °C	0.15 °C	
	(120 to 410) °C	0.15 °C	
	(410 to 1 300) °C	0.21 °C	
	Type R		
	(0 to 250) °C	0.46 °C	
	(250 to 400) °C	0.29 °C	
	(400 to 1 000) °C	0.26 °C	
	(1 000 to 1 767) °C	0.32 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type S (0 to 250) °C (250 to 1 000) °C (1 000 to 1 400) °C (1 400 to 1 767) °C Type T (-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C Type U (-200 to 0) °C (0 to 600) °C	0.45 °C 0.3 °C 0.29 °C 0.36 °C 0.49 °C 0.19 °C 0.13 °C 0.12 °C 0.44 °C 0.21 °C	Comparison to Fluke 5522A Multiproduct Calibrator
Capacitance – Source ¹ (Fixed Artifact)	1 kHz 10 pF	0.14 pF	Comparison to General Radio 1403G Standard Air Capacitor
Capacitance – Source ¹ (Variable Artifact)	1 kHz 100 pF to 1 nF (1 to 2) nF (2 to 10) nF (10 to 100) nF 100 nF to 1.111 µF	0.18 % of reading + 0.58 pF 0.15 % of reading + 0.17 pF 0.12 % of reading + 0.17 pF 0.09 % of reading + 58 fF 0.08 % of reading + 58 fF	Comparison to General Radio 1423A Decade Capacitance Box
Capacitance – Source ¹ (Simulation)	(220 to 400) pF 10 Hz to 10 kHz (0.4 to 1.1) nF 10 Hz to 10 kHz (1.1 to 3.3) nF 10 Hz to 3 kHz (3.3 to 11) nF 10 Hz to 3 kHz (11 to 33) nF 10 Hz to 1 kHz (33 to 110) nF 10 Hz to 1 kHz	0.4 % of reading + 7.8 pF 0.4 % of reading + 7.8 pF 0.4 % of reading + 7.8 pF 0.21 % of reading + 7.8 pF 0.2 % of reading + 78 pF 0.21 % of reading + 78 pF	Comparison to Fluke 5522A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source ¹ (Simulation)	(110 to 330) nF 10 Hz to 1 kHz	0.2 % of reading + 0.23 nF	Comparison to Fluke 5522A Multiproduct Calibrator
	(0.33 to 1.1) μ F (10 to 600) Hz	0.21 % of reading + 0.78 nF	
	(1.1 to 3.3) μ F (10 to 300) Hz	0.21 % of reading + 2.3 nF	
	(3.3 to 11) μ F (10 to 150) Hz	0.2 % of reading + 7.8 nF	
	(11 to 33) μ F (10 to 120) Hz	0.32 % of reading + 23 nF	
	(33 to 110) μ F (10 to 80) Hz	0.37 % of reading + 78 nF	
	(110 to 330) μ F DC to 50 Hz	0.38 % of reading + 0.23 μ F	
	(0.33 to 1.1) mF DC to 20 Hz	0.35 % of reading + 0.78 μ F	
	(1.1 to 3.3) mF DC to 6 Hz	0.35 % of reading + 2.3 μ F	
	(3.3 to 11) mF DC to 2 Hz	0.35 % of reading + 7.8 μ F	
	(11 to 33) mF DC to 0.6 Hz	0.58 % of reading + 23 μ F	
	(33 to 110) mF DC to 0.2 Hz	0.85 % of reading + 78 μ F	
Oscilloscopes ^{1,3} Amplitude – DC into 50 Ω load into 1 M Ω load Amplitude – Square Wave into 50 Ω load into 1 M Ω load	(-6.6 to 6.6) V (-130 to 130) V	0.22 % of reading + 31 μ V 0.12 % of reading + 31 μ V	Comparison to Fluke 5522A/SC1100 Multiproduct Calibrator
	10 Hz to 100 kHz 1 mVp-p to 6.6 Vp-p	0.22 % of reading + 31 μ V	
	10 Hz to 1 kHz 1 mVp-p to 130 Vp-p	0.14 % of reading + 31 μ V	
	(1 kHz to 10) kHz 1 mVp-p to 130 Vp-p	0.22 % of reading + 31 μ V	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes ^{1,3} Time Markers into 50 Ω load	1 ns to 20 ms 50 ms 0.1 s 0.2 s 0.5 s 1 s 2 s 5 s	0.000 22 % of reading 0.005 9 % of reading 0.009 8 % of reading 0.018 % of reading 0.041 % of reading 0.08 % of reading 0.16 % of reading 0.39 % of reading	Comparison to Fluke 5522A/SC1100 Multiproduct Calibrator
Rise Time into 50 Ω load Rate: 1 kHz to 2 MHz Rate: 2 MHz to 10 MHz	5 mVp-p to 2.5 Vp-p (200 to 300) ps (250 to 350) ps	50 ps 50 ps	
Leveled Sine Wave into 50 Ω load	5 mVp-p to 5.5 Vp-p 50 kHz 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5 mVp-p to 3.5 Vp-p 600 MHz to 1.1 GHz	1.8 % of reading + 0.23 mV 2.8 % of reading + 0.23 mV 3.2 % of reading + 0.23 mV 4 % of reading + 0.23 mV 5.5 % of reading + 0.23 mV	
Bandwidth/Flatness (50 kHz Reference) into 50 Ω load	5 mVp-p to 5.5 Vp-p 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5.0 mVp-p to 3.5 Vp-p 600 MHz to 1.1 GHz	1.4 % of reading + 78 μ V 1.8 % of reading + 78 μ V 3.2 % of reading + 78 μ V 4 % of reading + 78 μ V	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes ^{1,3} Input Impedance – Measure	(40 to 60) Ω 500 k Ω to 1.5 M Ω	0.082 % of reading 0.081 % of reading	Comparison to Fluke 5522A/SC1100 Multiproduct Calibrator
Input Capacitance – Measure	(5 to 50) pF	3.9 % of reading + 0.39 pF	
Waveform Generator (Sine, Square, Triangle) Amplitude into 50 Ω load into 1 M Ω load	10 Hz to 10 kHz 1.8 mVp-p to 2.5 Vp-p 1.8 mVp-p to 55 Vp-p	2.3 % of reading + 78 μ V 2.3 % of reading + 78 μ V	
Waveform Generator (Sine, Square, Triangle) Frequency	10 Hz to 10 kHz	0.001 9 % of reading + 12 mHz	

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gauge Blocks ²	Up to 4 in (5 to 20) in Up to 100 mm (125 to 500) mm	(1.2 + 1.5L) μ in (1.7 + 0.9L) μ in (30 + 1.5L) nm (43 + 0.9L) nm	Comparison to Gauge Block Comparator, Master Gauge Blocks, Master Long Gauge Blocks
Outside Micrometers ^{1,2}	Up to 6 in (6 to 60) in	(30 + 2L) μ in (60 + 5L) μ in	Comparison to Gauge Blocks, Long Gauge Blocks
Inside Micrometers ¹	Up to 24 in (24 to 60) in	300 μ in 400 μ in	Comparison to Height Master, Surface Plate
Depth Micrometers ^{1,2}	Up to 12 in	350 μ in	Comparison to Height Master, Surface Plate
Anvil Flatness ^{1,2}	Up to 1 inD	9.3 μ in	Comparison to Optical Flat
Anvil Parallelism ^{1,2}	Up to 1 inD	12 μ in	Comparison to Optical Parallel

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Calipers ¹			
Outside Diameter	Up to 12 in (12 to 24) in (24 to 40) in	300 μ in 430 μ in 460 μ in	Comparisons to Gauge Blocks
Inside Diameter, Depth, Step	Up to 12 in	300 μ in	Gauge Blocks, Gauge Block Accessories, Surface Plate
Jaw Parallelism	Up to 1 in	7.2 μ in	Cylindrical Pin Gauges
Bore Gauges ^{1,2}	Up to 8 in	(75 + 2L) μ in	Comparison to Characterized Cylindrical Rings
Digital/Dial Indicators, Test Indicators ¹			
0.001 in resolution	Up to 4 in	160 μ in	Comparison to Dial Indicator Calibrator
0.000 1 in resolution	Up to 1 in	24 μ in	
0.000 01 in resolution	Up to 0.025 in	10 μ in	
Electronic Linear Displacement Probes ²	Up to 100 mm	(0.031 + 0.003 1L) μ m	Comparison to Gauge Blocks
Height Gauges/Stands ^{1,2}	Up to 40 in	(240 + 1.2L) μ in	Comparison to Height Master, Surface Plate
Step Gauges, Micrometer Setting Standards ^{1,2}	Up to 60 in	(35 + 1.3L) μ in	Comparison to Master Step Gauge using Linear Probe, Amplifier, Surface Plate
Height Master, Riser Blocks ^{1,2}	Up to 24 in	(35 + 1.3L) μ in	Comparison to Gauge Blocks using Linear Probe, Amplifier, Surface Plate
Thread Wires	Up to 1 in	13 μ in	Comparison to SIP Measuring Machine
Cylindrical Plug Gauges ²			
Outside Diameter	Up to 12 in	(16 + 5L) μ in	Comparison to SIP Measuring Machine
Cylindrical Pin Gauges			
Outside Diameter	Up to 1 in	25 μ in	Comparison to Non-contact Measurement using Laser Micrometer

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Cylindrical Ring Gauges ² Inside Diameter	Up to 12 in	$(16 + 5L) \mu\text{in}$	Comparison to Sip Measuring Machine
Thread Plug Gauges, Thread Setting Plug Gauges ² Pitch Diameter – 60° Thread	Up to 1.5 in (1.5 to 6) in (6 to 12) in	100 μin 200 μin 300 μin	Comparisons to SIP Measuring Machine, Thread Wires
Major Diameter	Up to 12 in	$(16 + 5L) \mu\text{in}$	SIP Measuring Machine, Master Plug Gauge
Step Height	Up to 1 in	40 μin	Height Master using Electronic Probe, Amplifier, Surface Plate
Adjustable Thread Ring Gauges ³ Pitch Diameter – 60° Thread	Up to 1.5 in (1.5 to 6) in (6 to 12) in	See Footnote 3	Tactile Fit using Thread Setting Plug Gauge
Pipe Thread Plug Gauges Simple Pitch Diameter (4 to 80) TPI	Up to 1.5 in (1.5 to 6) in	100 μin 200 μin	Comparisons to SIP Measuring Machine, Master Plug Gauge, Thread Wires
Step Height	Up to 2 in	40 μin	Height Master using Electronic Probe, Amplifier, Surface Plate
Pipe Thread Ring Gauges Standoff to Master	Up to 6 in	0.001 in	Per ASME 1.20.1, ASME B1.20.5
Thickness	N/A	100 μin	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Pipettes			
Single Channel	(0.2 to 2) μ l (2 to 10) μ l (10 to 20) μ l (20 to 100) μ l (100 to 200) μ l (200 to 1 000) μ l (1 to 5) ml (5 to 10) ml (10 to 50) ml	17 nl 21 nl 25 nl 0.1 μ l 0.14 μ l 0.76 μ l 4.4 μ l 5.9 μ l 7.6 μ l	Gravimetric Method using Electronic Balances.
Multi-Channel	(2 to 20) μ l (2 to 200) μ l (200 to 1 000) μ l	0.31 μ l 0.36 μ l 0.76 μ l	
Torque Wrenches, Torque Screwdrivers ¹	10 ozf·in to 1 000 lbf·ft	1 % of reading	Comparison to Torque Calibration System
Pneumatic Gauge Pressure Devices	(-1.32 to 1.32) psig (-2.2 to 2.2) psig Up to 9 psig (9 to 30) psig Up to 300 psig (300 to 1 000) psig	0.000 15 psi 0.01 % of reading 0.000 73 psi 0.008 2 % of reading 0.031 psi 0.01 % of reading	Comparison to Fluke PPC4 Pressure Controller/ Calibrator, Fluke Reference Pressure Transducers
Absolute Pneumatic Pressure Devices	(-14.7 to 300) psia (300 to 1 000) psia	0.031 psi 0.01 % of reading	Comparison to Fluke PPC4 Pressure Controller/ Calibrator with Absolute Pressure Transducer, Built-in Barometric Pressure Reference Gauge
Hydraulic Gauge Pressure Devices	Up to 600 psig (600 to 3 000) psig (3 000 to 30 000) psig	0.12 psi 0.61 psi 0.02 % of reading	Comparison to Fluke RPM4-E-DWT Electronic Deadweight Tester

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Mass Determination (SI)	(1 to 200) mg 300 mg 500 mg 1 g 2 g 3 g 5 g 10 g 20 g 30 g 50 g 100 g 200 g 300 g 500 g 1 kg 2 kg 3 kg 5 kg 10 kg 20 kg 25 kg	2 µg 3 µg 4 µg 7 µg 7 µg 8 µg 10 µg 17 µg 33 µg 50 µg 40 µg 80 µg 0.1 mg 0.15 mg 0.15 mg 0.5 mg 2 mg 2.4 mg 2.5 mg 10 mg 20mg 30 mg	Modified Double Substitution using ASTM E617 Class 1 Weight Set and Electronic Balances.
Mass Determination (SI)	10 kg 20 kg 25 kg	40 mg 60 mg 70 mg	Single Substitution using ASTM E617 Class 1 Weight Set and Electronic Balances.
Scales and Balances ^{1,4} (Non-automatic)	1 mg 2 mg 5 mg 10 mg 20 mg 50 mg 100 mg 200 mg 500 mg 1 g 2 g 5 g 10 g	3 µg 3 µg 3 µg 3 µg 3 µg 3 µg 3 µg 3 µg 3 µg 5 µg 7 µg 7 µg 10 µg 19 µg	ASTM E617 Class 1 weights and internal calibration procedure utilized for the calibration of the weighing system.

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Scales and Balances ^{1,4} (Non-automatic)	(10 to 20) g	35 µg	ASTM E617 Class 1 weights and internal calibration procedure utilized for the calibration of the weighing system.
	(20 to 50) g	0.1 mg	
	(50 to 100) g	0.1 mg	
	(100 to 200) g	0.15 mg	
	(200 to 300) g	0.25 mg	
	(300 to 500) g	0.35 mg	
	(0.5 to 1.2) kg	2 mg	
	(1.2 to 8) kg	40 mg	
	(8 to 30) kg	80 mg	
	(30 to 60) kg	30 mg	
	(60 to 150) kg	3 g	
	(150 to 500) kg	30 g	
	(500 to 1000) kg	60 g	

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Infrared Thermometers ¹	(-15 to 0) °C	0.8 °C	Comparison to Fluke 4180, 4181 Blackbody Sources (Flat Plate) $\lambda = (8 \text{ to } 14) \mu\text{m}$, $\epsilon = (0.9 \text{ to } 1)$
	(0 to 50) °C	0.65 °C	
	(50 to 100) °C	0.7 °C	
	(100 to 120) °C	0.76 °C	
	(120 to 200) °C	0.94 °C	
	(200 to 350) °C	1.6 °C	
	(350 to 500) °C	2.1 °C	
Liquid Baths, Drywells ¹	(-200 to 630) °C	0.1 °C	Comparison to SPRT, Black Stack Thermometer
Ovens, Furnaces ¹	(-50 to 0) °C	1.5 °C	Comparison to Type K Thermocouple, Digital Indicator
	(0 to 275) °C	0.06 % of reading + 1.6 °C	
	(275 to 760) °C	0.47 % of reading + 1 °C	
Digital Thermometers with RTD, PRT, and Thermistor Probes ¹	(-30 to 50) °C	0.15 °C	Comparison to SPRT, Black Stack Thermometer, Dry-well
	(50 to 150) °C	0.17 °C	
	(150 to 450) °C	0.5 °C	
	(450 to 650) °C	0.65 °C	
Digital Thermometers with Thermocouple Probes ¹	(-30 to 50) °C	0.3 °C	Comparison to SPRT, Black Stack Thermometer, Dry-well
	(50 to 155) °C	0.4 °C	
	(155 to 660) °C	0.066 % of reading + 0.67 °C	

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Humidity – Measure ¹	(-10 to 70) °C (10 to 90) %RH (90 to 95) %RH	3.1 %RH 4 %RH	Comparison to Vaisala HMI41/HMP45 Temp/Humidity Indicator/Probe
Temperature/Humidity Measuring Devices Temperature – Generate Humidity – Generate	(-10 to 70) °C (-10 to 15) °C (10 to 75) %RH (75 to 95) %RH 15 to 35) °C (10 to 95) %RH (35 to 70) °C (10 to 50) %RH (50 to 75) %RH (75 to 95) %RH	0.1 °C 0.5 %RH 0.65 %RH 0.5 %RH 0.5 %RH 0.7 %RH 0.85 %RH	Comparison to Thunder Scientific 2500 Two-Pressure Humidity Generator

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Contact Tachometers ²	(55 to 350) rpm (351 to 1 499) rpm (1 500 to 3 000) rpm (3 001 to 5 000) rpm (5 001 to 10 000) rpm (10 001 to 15 000) rpm (15 001 to 40 000) rpm	0.12 rpm 0.11 rpm 0.3 rpm 0.39 rpm 0.8 rpm 1.8 rpm 3.4 rpm	Comparison to Contact Tachometer Calibration System
Non-contact Tachometer ^{1,2}	(6 to 60) rpm (60 to 600) rpm (600 to 99 999) rpm	0.005 3 % of reading 0.000 75 % of reading 0.000 3 % of reading	Comparison to LED, Multiproduct Calibrator
Frequency – Reference ¹	10 MHz	23 pHz/Hz	Comparison to Pendulum FTR-210R Discipline Rubidium Frequency and Time Reference

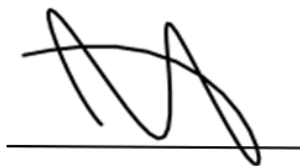
Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Measure ¹	(1 to 10) Hz 10 Hz to 1 kHz 1 kHz to 1.3 GHz	11 μ Hz 90 nHz/Hz + 10 μ Hz 0.1 μ Hz/Hz	Comparison to Fluke PM6681 Timer/Counter/Analyzer, Pendulum FTR-210R Discipline Rubidium Frequency and Time Reference
Period – Measure ¹	(1 to 9) s	9.8 μ s/s + 1.2 μ s	Comparison to Fluke PM6681 Timer/Counter/Analyzer, Pendulum FTR-210R Discipline Rubidium Frequency and Time Reference
Stopwatches, Timers ¹	Up to 599 s/day	60 ms/day	Comparison to Helmut Klein TM4500 Timometer

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

- On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
- L = length in inches or mm; D = diameter in inches; rpm = revolutions per minute.
- The “tactile fit” setting of an adjustable thread ring with a thread setting plug is not a measurement of pitch diameter. The uncertainty for this pitch diameter setting is based on the contributors associated with the thread setting plug and environmental conditions only.
- The CMC for scales and balances is highly dependent upon the resolution of the unit under test. The CMC presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
- The legal entity name for this client is Transcat, Inc.
- Unless otherwise specified in the far-right column, the calibration procedure/method utilized by the laboratory was internally written.



Jason Stine, Vice President